

7th Workshop on Test of Wireless Circuits and Systems

WTW2008 Technical Program

April 27th, 2008

Rancho Bernardo Inn Golf Resort & Spa, San Diego, CA, USA

www.wtw2008.tec.ufl.edu/

8:30am-8:45am	Opening Address	Prog. Chair: Mustapha Slamani Gen. Chair: Rob Aitken	IBM ARM
Session I	Keynote Speaker & Invited Speaker		
8:45AM-9:30AM	The Convergence of Media and Telecommunications Pushing Ahead	Christopher Douglass, Wireless Strategy and Next Gen Solution Executive	IBM Global Telecommunications
9:30AM-10:00AM	SiP/SoC Test Challenges	Octavio Martinez	Qualcomm
10:00AM-10:30AM	Coffee break/Refreshment Student Poster Session		
Session II	Non-Traditional Test Techniques		
10:30AM-11:00AM	Towards 100Gbps: Scaling Trends for High-Performance ATE	David Keezer	Georgia Tech
11:00AM-11:30AM	Hybrid Non-Contact Testing for Advanced Packaging	Brian Moore	Scanmetrics Inc
11:30AM-12:00AM	Optimized Implementations of DC Testing for RF products	Salem Abdennadher	Intel
12:00PM-1:00PM	Lunch Break		
Session III	On-Chip/On-Board DFT		
1:00PM-1:30PM	Testing the DigRF 3G Baseband to RF Interface: BIST Allows a Low Cost Production Solution	Larry Luce	Freescale
1:30PM-2:00PM	Automatic Matching Control System for Loadboard Test	Jaeseok Kim & William Eisenstadt Ho-Hsin Yeh & Kathleen Melde	Univ. of Florida Univ. of Arizona
2:00PM-2:30PM	Range Calibration and Phase Noise Characterization of a High-Performance PLL with Integrated VCO	C. Montiel, C. Pearson, K. Vasanth, C. Yots, & P. Arora,	Texas Instruments
2:30PM-3:00PM	Coffee break/Refreshment Student Poster Session		
Session IV	Reliability & Built-in Test for Embedded Communications Circuits		
3:00PM-3:30PM	HTOL/Latch-up Issues on RF-CMOS Products: A Case Study	Gaurav Verma	Qualcomm.
3:30PM-4:00PM	Loop-Back Mode for Characterization of an Audio CODEC for Mobile Application	A. Owzar, E. Baykal, N. Haandbaek, W. Groeteweg, M. Helfenstein	NXP
4:00PM-4:30PM	Robust RF BICS with Novel I-V Conversion Input Stage for 65-nm CMOS Technology	John Liobe & Martin Margala,	University of Massachusetts Lowell
4:30PM-5:00PM	Digitally-Assisted Analog/RF Testing for Wireless SoCs: A Weaver Image-Reject Receiver Case Study	Hsiu-Ming (Sherman) Chang & Kwang-Ting (Tim) Cheng Min-Sheng (Mitchell) Lin	University of California, Santa Barba Broadcom
5:00PM-5:30PM	Student Poster Session		